



3rd Annual International Workshop on
Grid Simulator Testing
of
Energy Systems and Wind Turbine Power Trains



Lessons Learned from PHIL Experiments with Power Converters and Fault Current Limiters

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Overview



I. PHIL

II. Lessons Learned

I. Stability

II. Engagement of PHIL Interfaces

III. Accuracy

IV. Flexibility of PHIL Interfaces

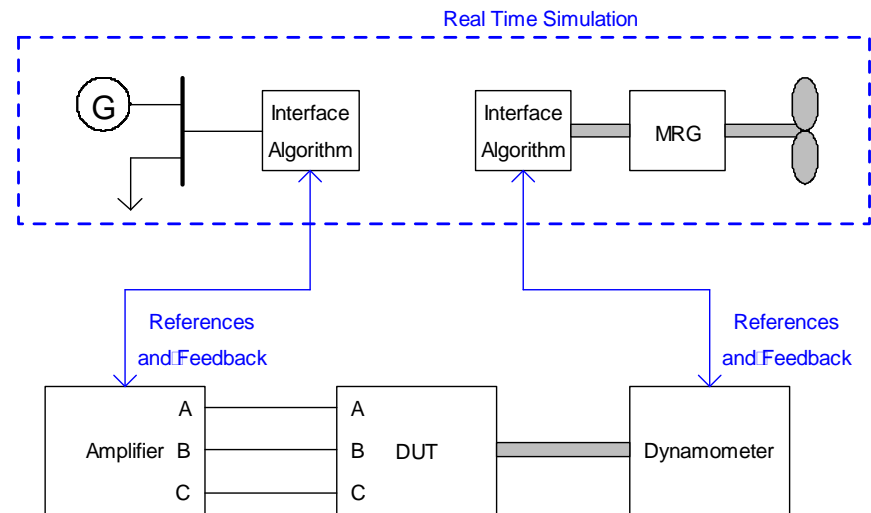
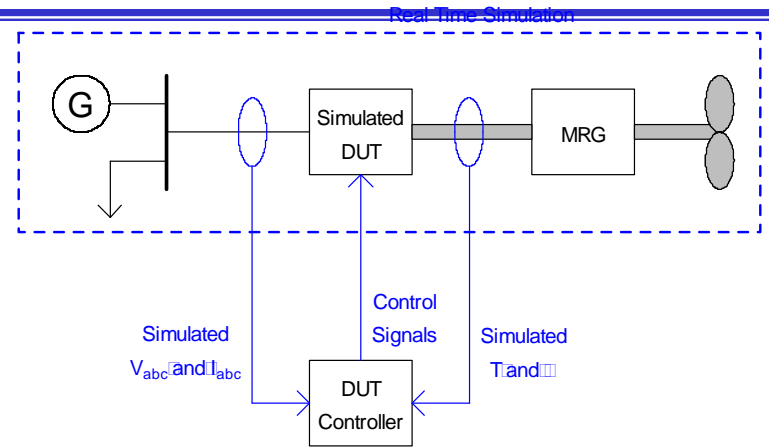
V. Protection of PHIL Experiments

VI. Other Points

III. Conclusion

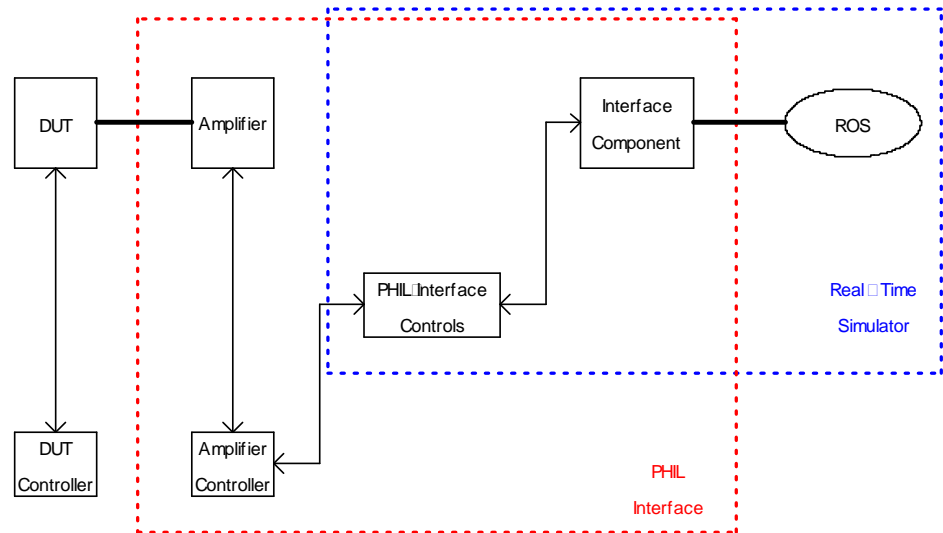
HIL Simulation Approach

- A device under test (DUT) is interfaced to a simulated environment through HIL interfaces to a real-time simulation model
- Allows
 - DUT to be exercised in a wide range of potentially realistic environments
 - Execution of extreme conditions within controlled lab environment
 - DUT to be tested with systems not yet constructed
 - DUT to be exercised to extremes of interface specifications including controlled transients
- Controller HIL (CHIL)
 - HIL Interfaces use control level (low voltage) signals for I/O
- Power HIL (PHIL)
 - Power amplifiers and/or actuators are used for interfacing
 - Power flow over PHIL interface



- Non-ideal interfaces

- Time delays associated with I/O, controllers for actuators and amplifiers, etc.
- Limited bandwidth of amplifiers and actuators



- Restrictions of real-time simulation

- Typically fixed time-step size simulations with minimum achievable time-step size
- Limitations on the size and complexity of simulated systems due to finite computational resources

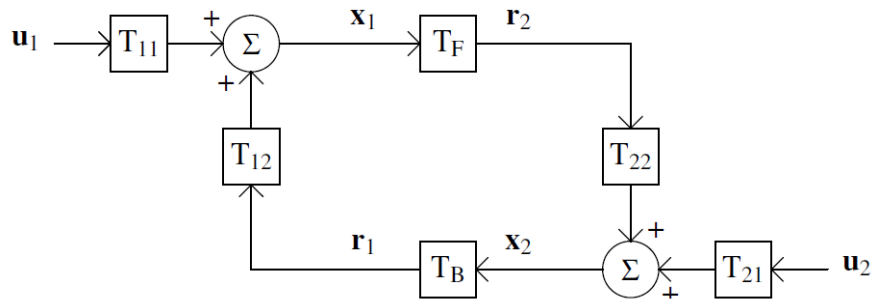
- Limitations of amplifiers and actuators (max power, torque, speed, etc.)

- Assessment of the impact of HIL Interfaces (particularly PHIL)

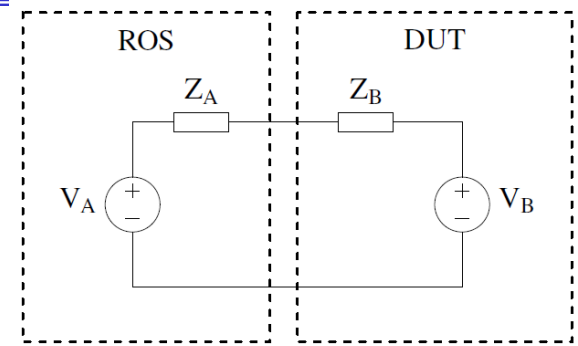
- Accuracy of models used for surroundings

- Common issue with modeling and simulation activities, in general – establishing confidence in the models.
- Synergy between model verification and validation (V&V) and HIL simulation

Stability of PHIL Experiments



PHIL System [1]

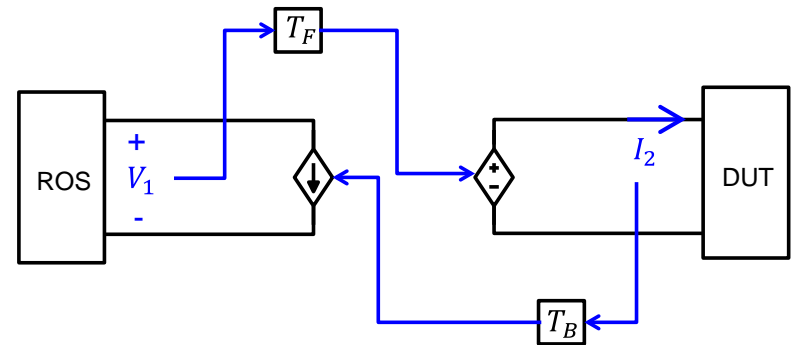


Example ROS and DUT

$$W = -1 + \det(I + G_{OL}) \quad [2]$$

$$G_{OL-ITM-VT} = -\frac{Z_A}{Z_B} T_{mI} T_A$$

$$G_{OL-ITM-IT} = -\frac{Z_B}{Z_A} T_{mV} T_A$$

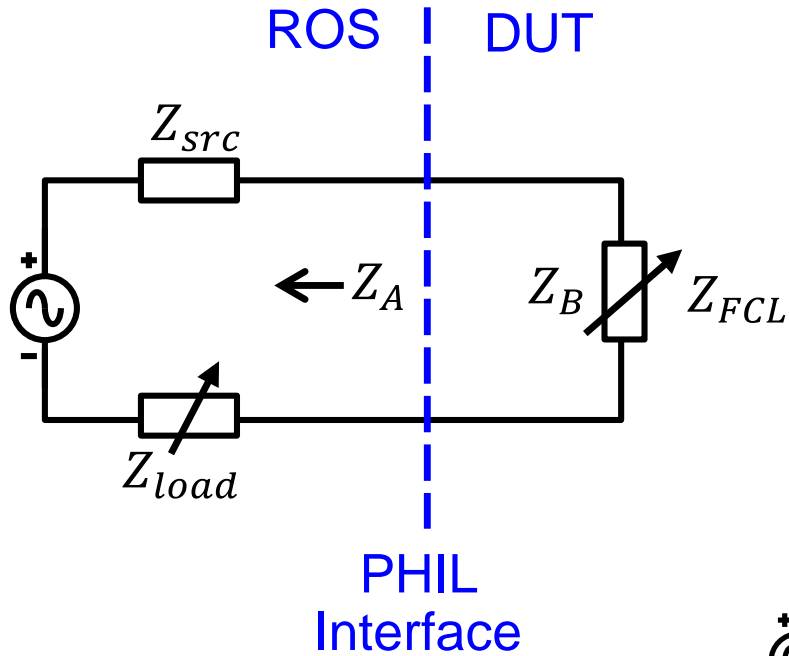


Voltage Type Ideal Transformer Model Interface Algorithm

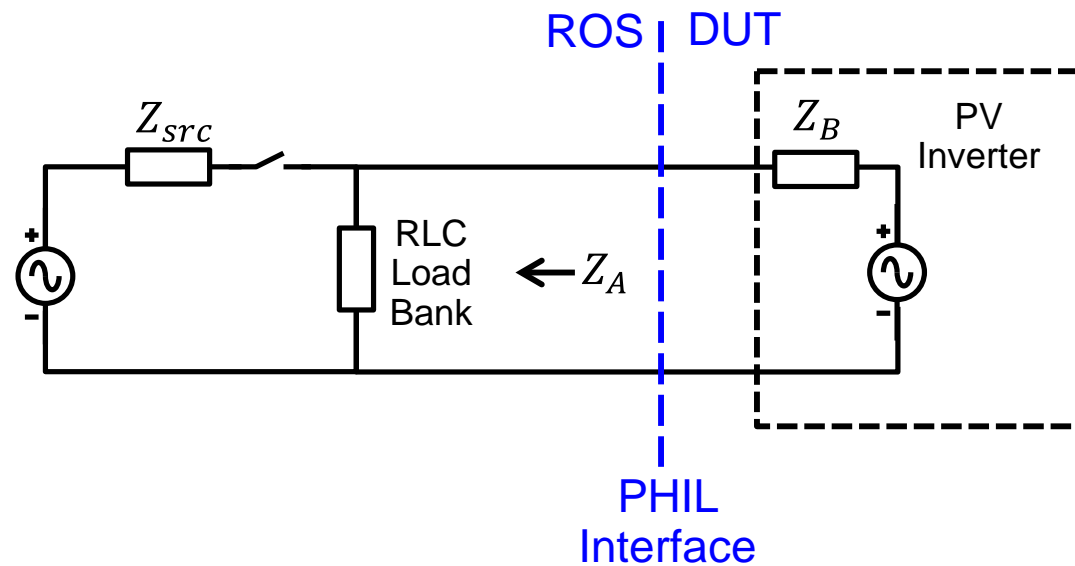
[1] Wei Ren, M. Steurer, and T.L. Baldwin. Improve the stability and the accuracy of power hardware-in-the-loop simulation by selecting appropriate interface algorithms. *Industry Applications, IEEE Transactions on*, 44(4):1286-1294, July 2008.

[2] Alexander Viehweider, Felix Lehfuss, and Georg Lauss. Interface and stability issues for SISO and MIMO power hardware in the loop simulation of distribution networks with photovoltaic generation. *International Journal of Renewable Energy Research (IJRER)*, 2(4):631-639, 2012.

Fault Current Limiters



Island Detection Tests for PV Inverters





Engagement of PHIL Interfaces



DC ITM-IT IA

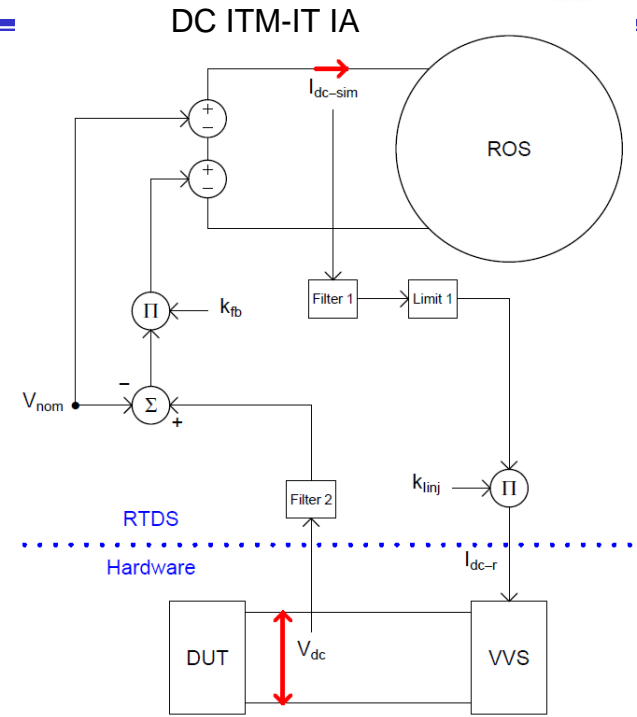
- Allow PHIL interfaces to be gradually engaged to couple DUT and simulated ROS
- Can allow stability issues to be detected prior to full instability
- Bring systems to steady state and allow for smooth transition to PHIL experiment
- Example: Testing a 1.2 MW, 4.16 kV AC / 1 kV DC Power Conversion Module for Shipboard Applications ([1] on next slide)

Surrounding System [1]

Current with ITM IA [1]

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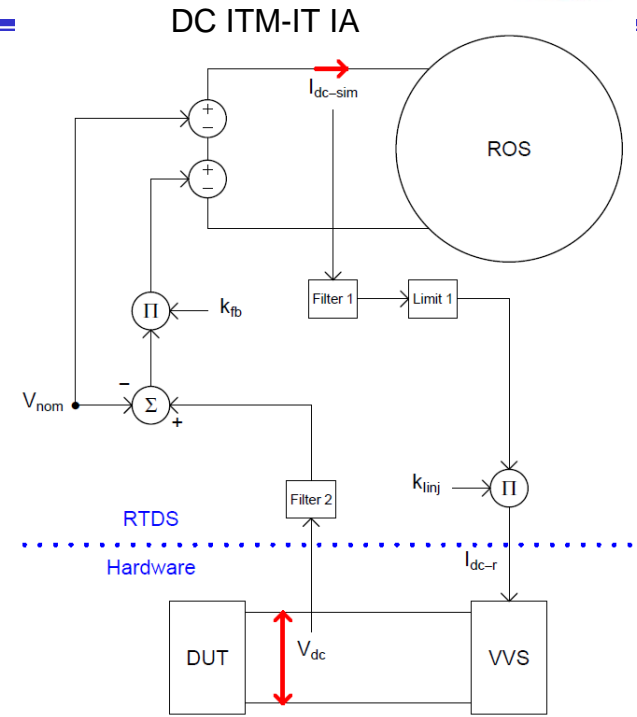


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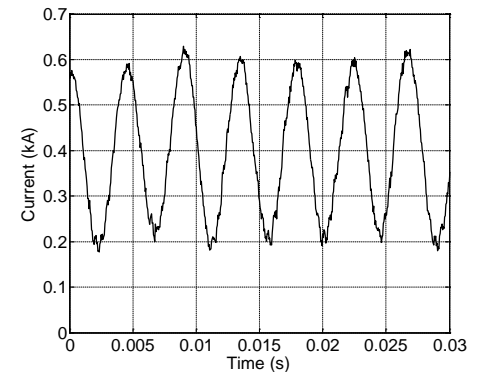
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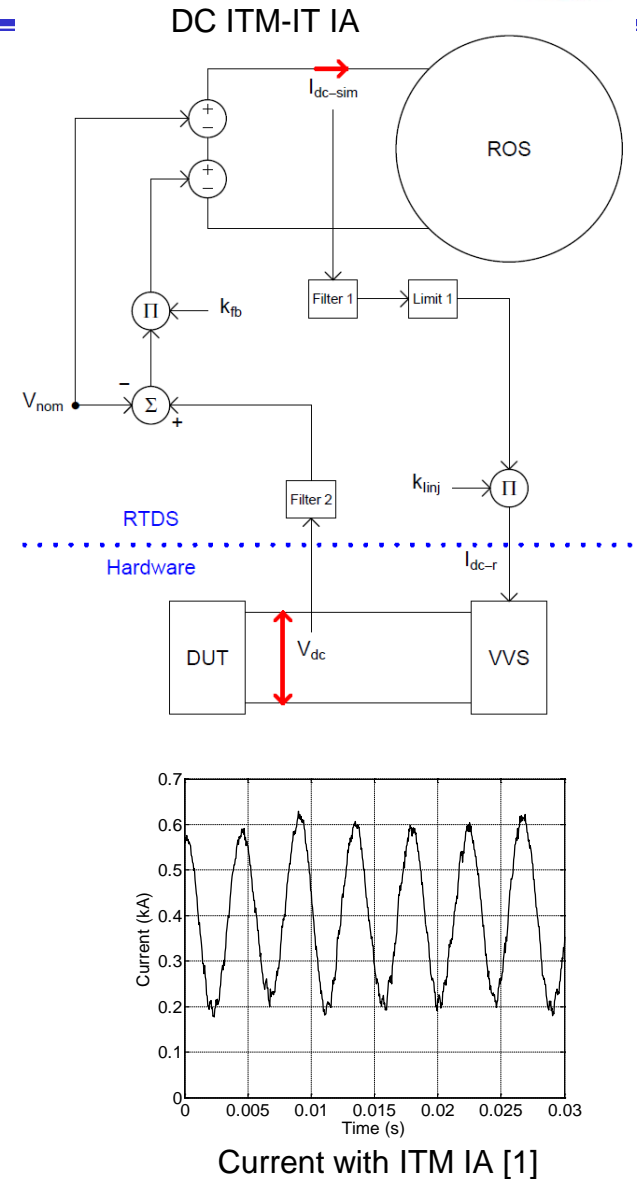
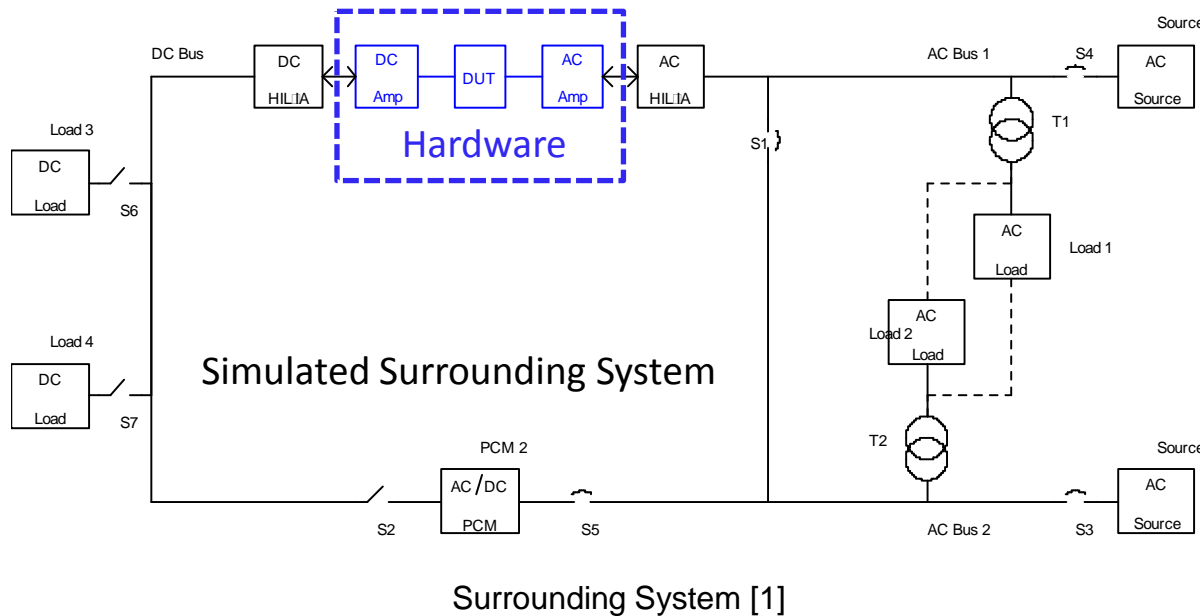
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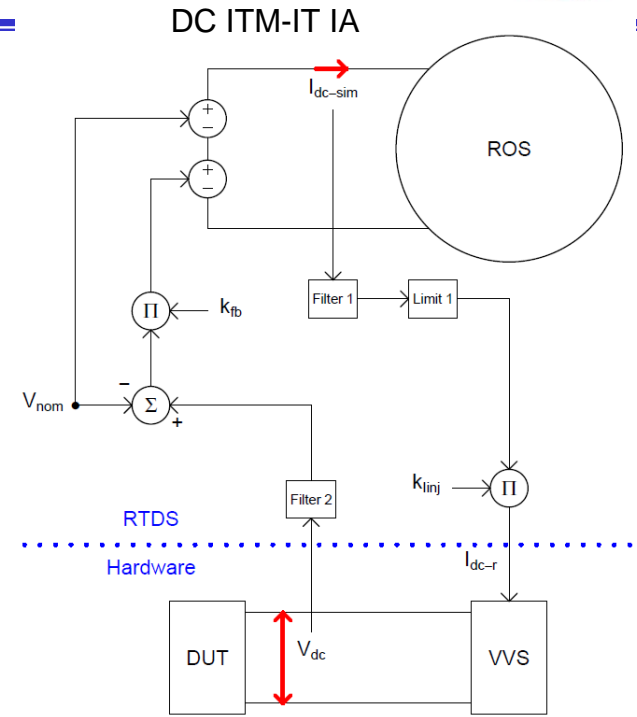
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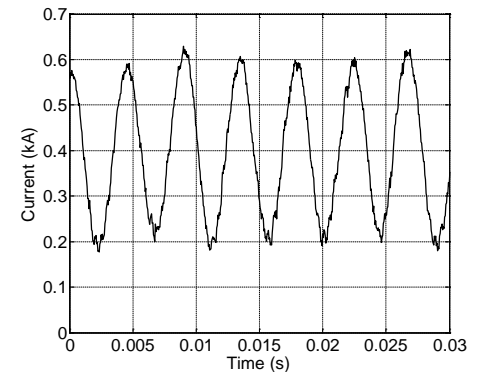


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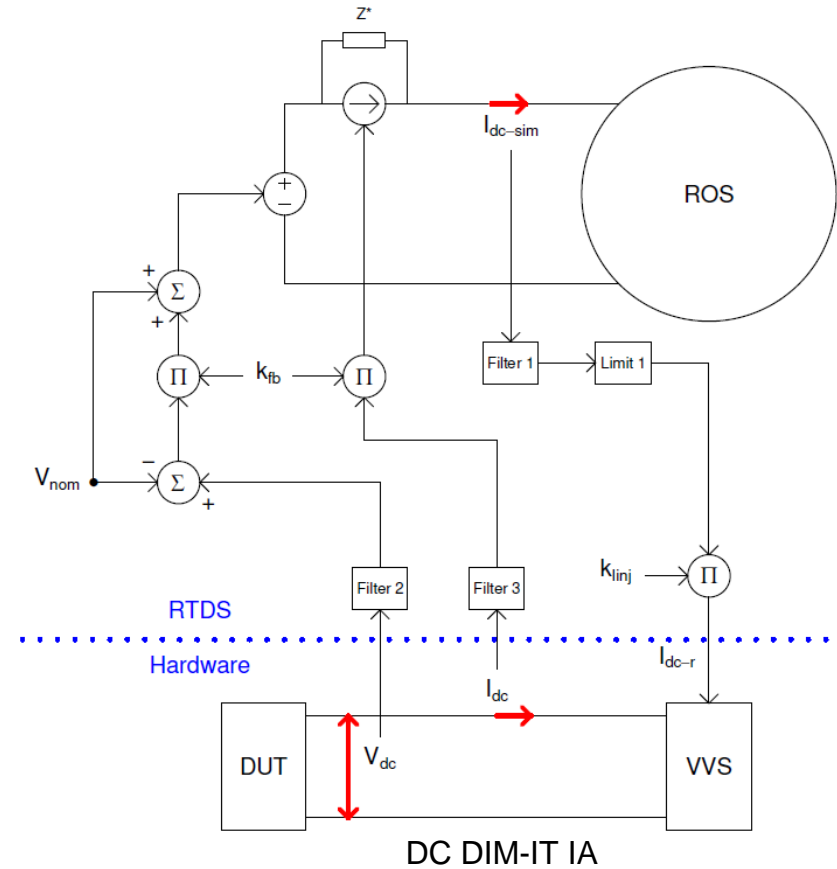
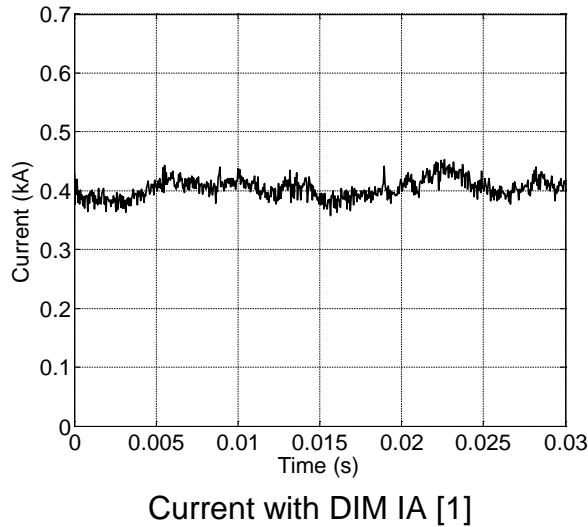


Surrounding System [1]



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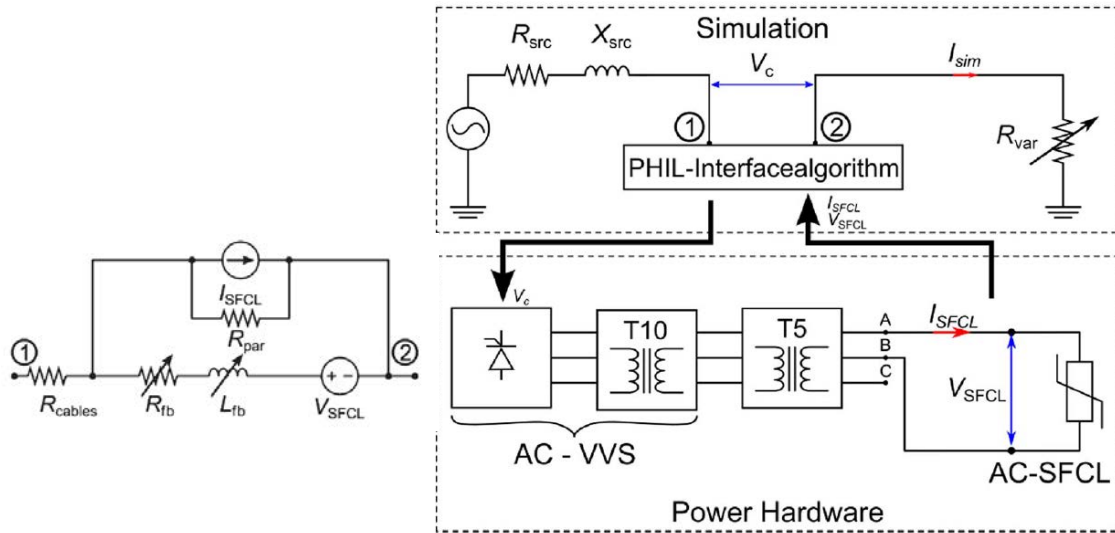
- Example: Testing a 1.2 MW, 4.16 kV AC / 1 kV DC Power Conversion Module for Shipboard Applications [1]
- Employed current-type Damping Impedance Method (DIM) IA [2]



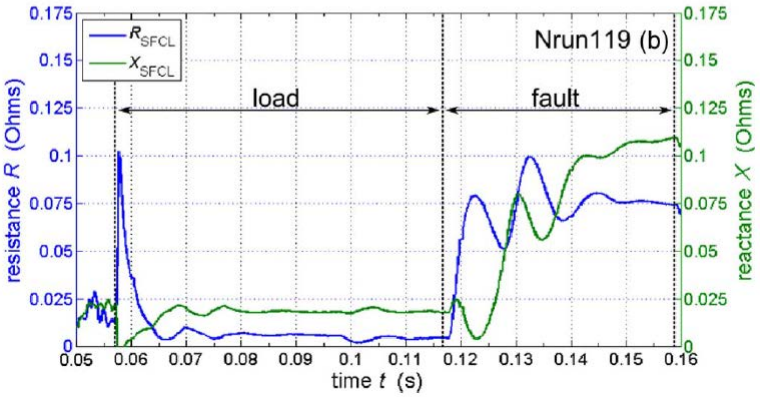
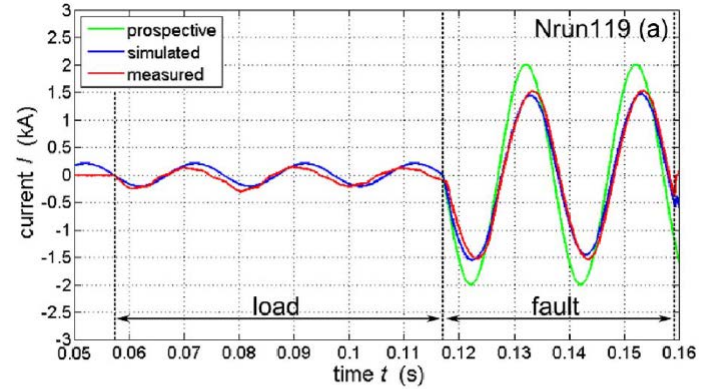
[1] J. Langston, F. Bogdan, J. Hauer, K. Schoder, M. Steurer, D. Dalessandro, T. Fikse, J. Cherry, and S. Gonstead, "Megawatt-scale power hardware-in-the-loop simulation testing of a power conversion module for naval applications," Electric Ship Technologies Symposium (ESTS), 2015 IEEE, pp.268,275, 21-24 June 2015.

[2] Richard Mack Mersenski. Evaluation of a new power-hardware-in-the-loop (PHIL) interface algorithm for current controlled amplifiers. Master's thesis, University of South Carolina, 2011.

- Example: PHIL Testing of Air Core Superconducting FCL [1]
- Used Modified DIM IA [2]
- Initialized damping impedance to known pre-quench impedance
- Used a few cycles of pre-fault, load current to allow the impedance to be estimated and all feedback of the IA engaged



PHIL Setup and ROS [1]



Voltage and DUT Impedance [1]

[1] Naeckel, O.; Langston, J.; Steurer, M.; Fleming, F.; Paran, S.; Edrington, C.; Noe, M., "Power Hardware-in-the-Loop Testing of an Air Coil Superconducting Fault Current Limiter Demonstrator," *Applied Superconductivity, IEEE Transactions on*, vol.25, no.3, pp.1,7, June 2015.

[2] Sanaz Paran and CS Edrington. Improved power hardware in the loop interface methods via impedance matching. In Electric Ship Technologies Symposium (ESTS), 2013 IEEE, pages 342-346. IEEE, 2013.



Accuracy



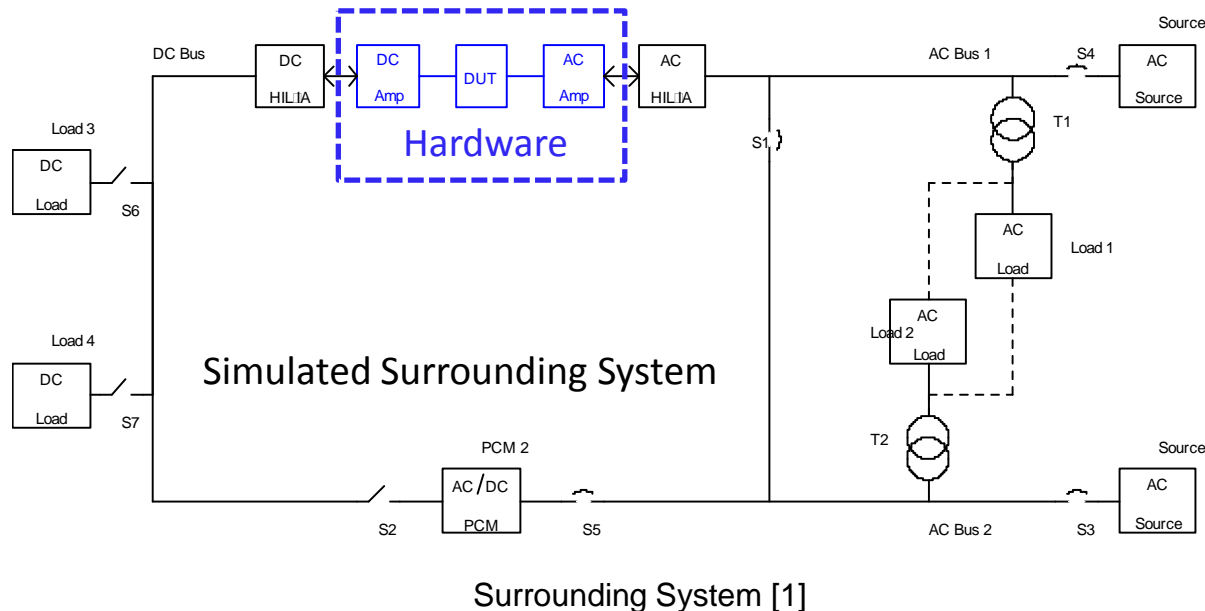
- Example: Load Rejection Test with 1.2 MW, 4.16 kV AC / 1 kV DC Power Conversion Module for Shipboard Applications ([1] on next slide)

Oscillations in Current
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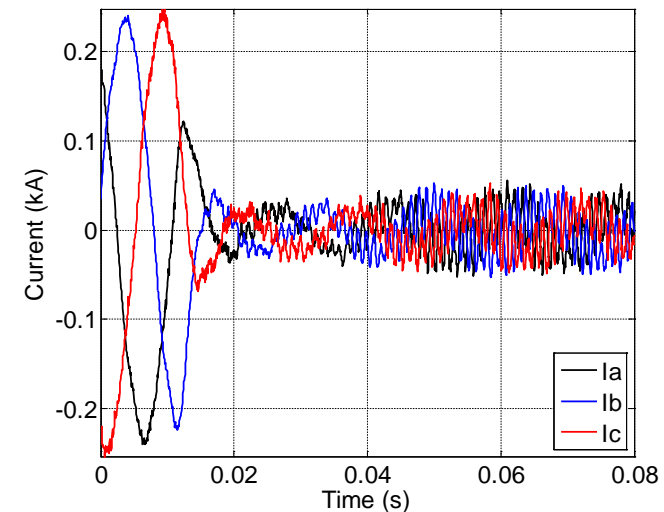
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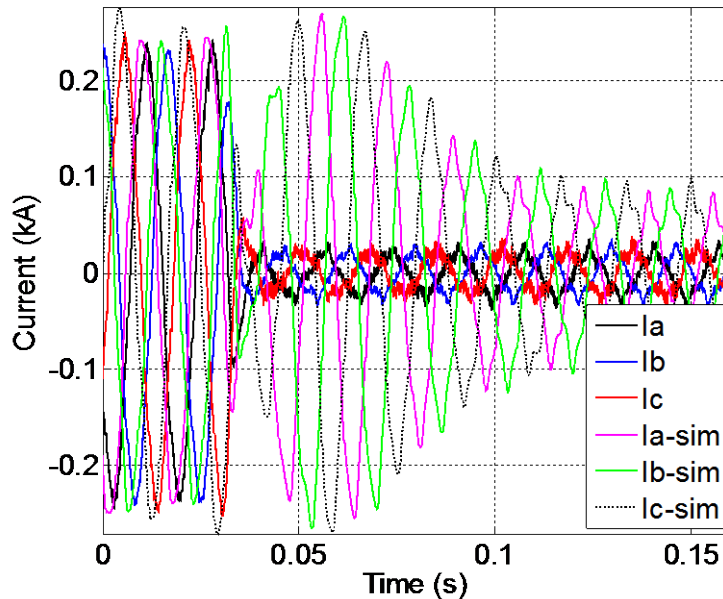
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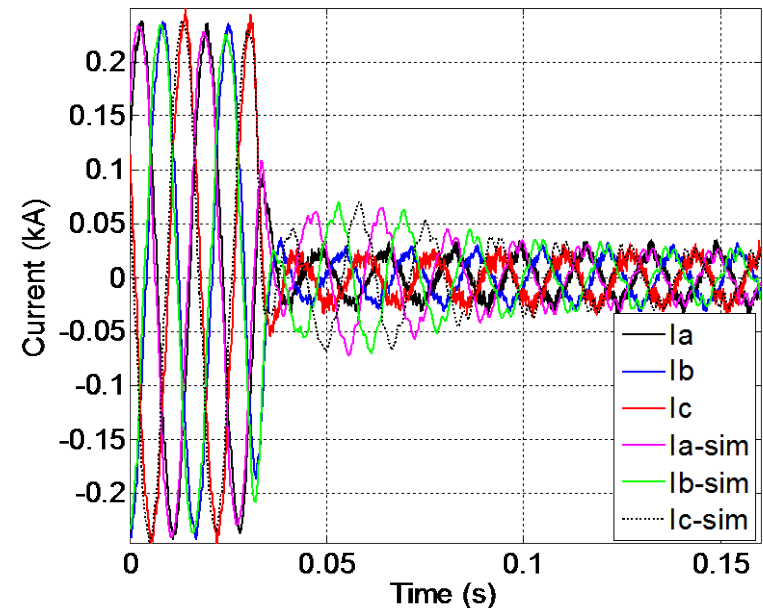
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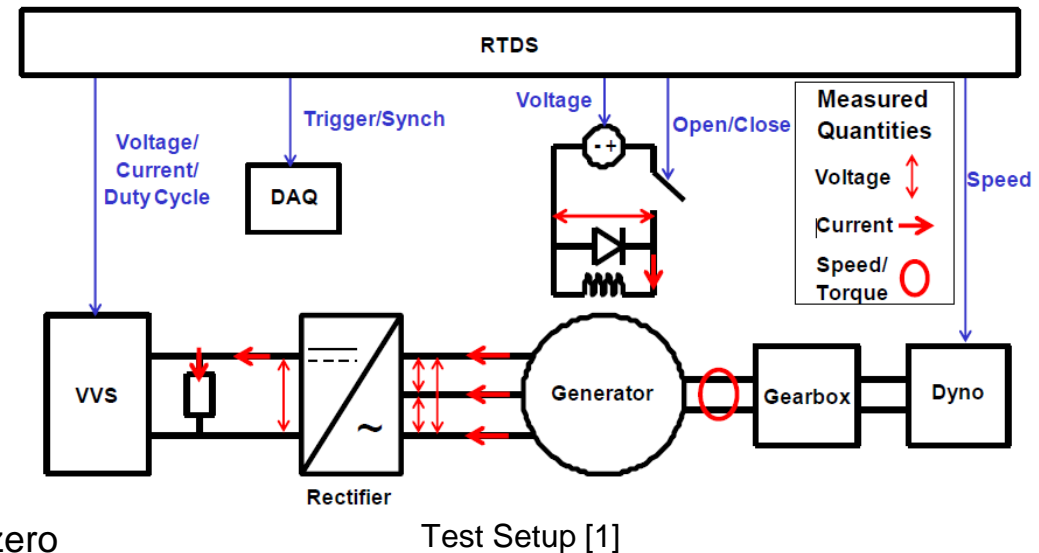
- Important to protect the DUT
- Gracefully shut down the experiment if a problem is encountered
- Take (only) appropriate actions in response to detected problems
- Example: Testing 1.2 MW, 15,000 RPM High Speed Generator [1]

- Protection Elements

- Over-voltage
- Over-current
- Over-speed
- Over-torque

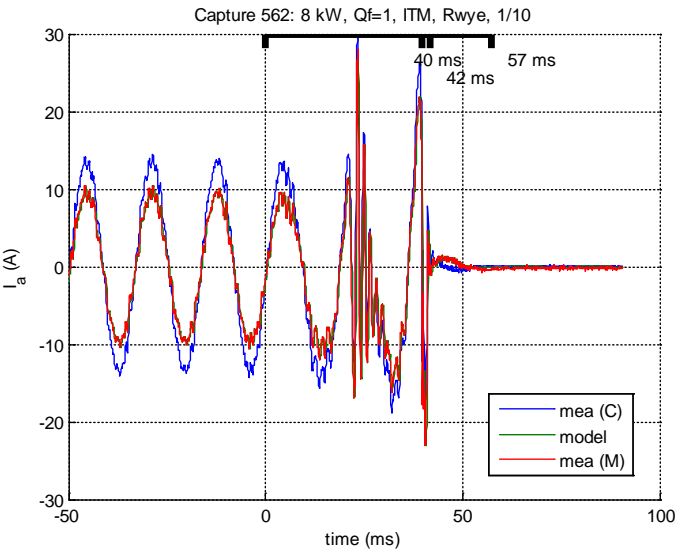
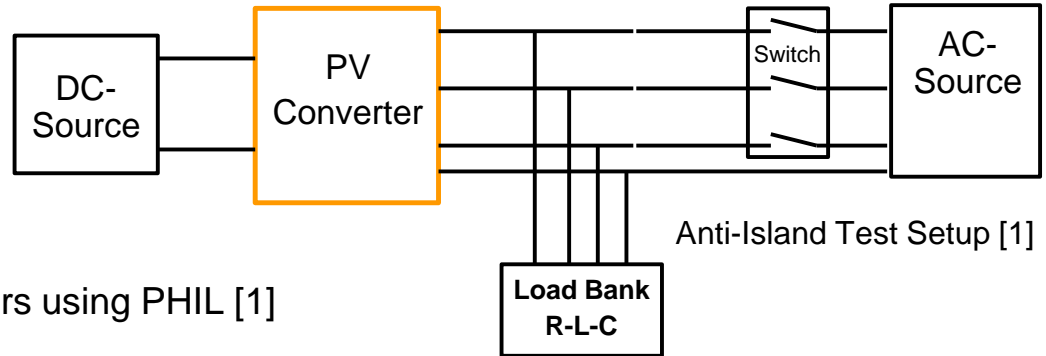
- Protection Actions

- Open closed-loop controls
- Open excitation switch
- Ramp VVS (load) current to zero
- Ramp dynamometer speed to zero
- Step dynamometer speed reference to zero

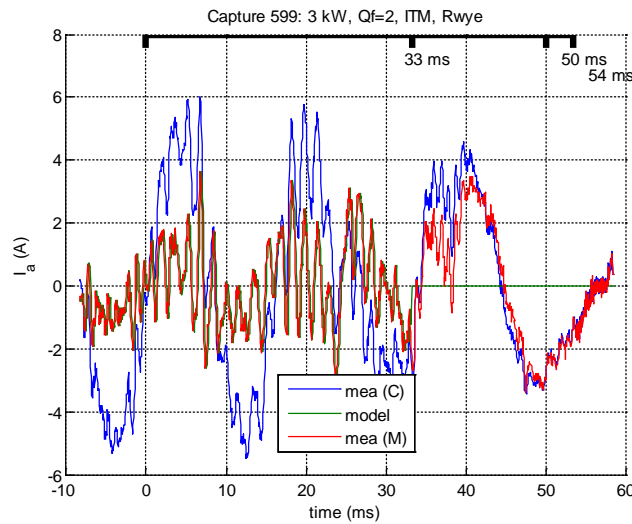


[1] J. Langston, M. Steurer, K. Schoder, J. Hauer, F. Bogdan, I. Leonard, T. Chiochio, M. Sloderbeck, A. Farrell, J. Vaidya, and K. Yost, "Megawatt Scale Hardware-in-the-Loop Testing of a High Speed Generator," Proc. 2012 ASNE Day, Arlington, VA, February 9-10, 2012.

- Methods to detect the onset of instability
 - Frequency
 - Voltage/current distortion
 - Time-based
 - Others
- Example: Anti-Islanding Tests of PV Inverters using PHIL [1]



Stable Case [1]



Marginally Stable Case [1]

[1] M. Steurer, K. Schoder, J. Langston, J. Hauer, and B. Mather, "Progress on Power Hardware-in-the-Loop Based Anti-Islanding Testing of PV Converters," Presentation at the Second International Workshop on Grid Simulator Testing of Wind Turbine Drivetrains, September 17-18, 2014, North Charleston, South Carolina, USA.



Other Points

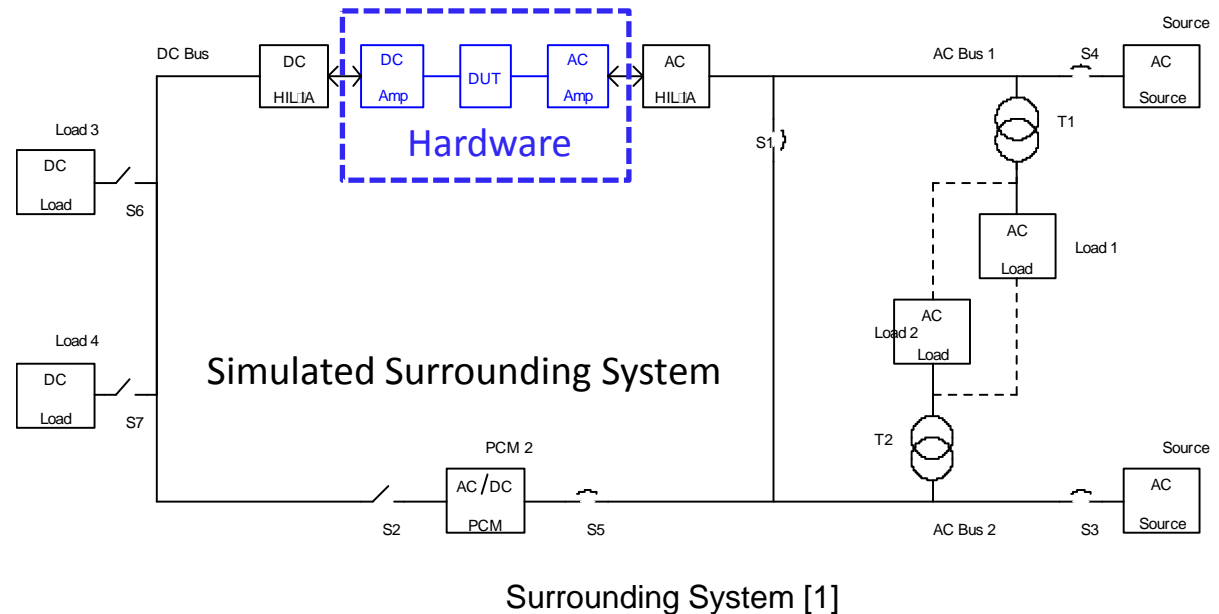


- Simulation Mode
- Information Collection
 - Capture Reference Signals
 - Collect Trending Information Including Settings
- Minimize Surrounding System
- Detailed Checklists and Procedures
- Attention to Detail

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Conclusions

- Stability and Accuracy Key for PHIL Experiments
- Points
 - Stability
 - Engagement of PHIL Interfaces
 - Accuracy
 - Flexibility of PHIL Interfaces
 - Protection of PHIL Experiments
 - Simulation Mode
 - Information Collection
 - Minimize Surrounding System
 - Detailed Checklists and Procedures
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